

Title (en)  
HIGH SPATIAL RESOLUTION INFRARED ELLIPSOMETER

Title (de)  
INFRAROT-ELLIPSOMETER MIT HOHER RÄUMLICHER AUFLÖSUNG

Title (fr)  
ELLIPSOMETRE A HAUTE RESOLUTION SPATIALE FONCTIONNANT DANS L'INFRAROUGE

Publication  
**EP 1301764 A1 20030416 (FR)**

Application  
**EP 01949572 A 20010628**

Priority  
• FR 0102072 W 20010628  
• FR 0009318 A 20000717

Abstract (en)  
[origin: WO0206779A2] The invention concerns a spectroscopic ellipsometer comprising: a source (2) capable of emitting a broadband ray (4), a polarizer (10) for polarizing the broadband beam (4), and for producing a polarised incident beam (12) adapted to illuminate a sample (16) according to at least a selected angle; an analyzer (24) for receiving the beam reflected (20) by the illuminated sample (16) and for producing an output beam (28) in response to said reflected beam (20); and at least a reflecting optical element (14) arranged between the source (2) and the sample (16) and/or between the sample (16) and the sensor, and capable of focusing the incident beam (12) and/or the reflected ray (20) according to a selected spot. The ellipsometer further comprises at least a first refracting element (22) arranged between the sample (16) and the sensor and/or between the source (2) and the sample (16) to collect and focus said reflected beam and/or said incident beam, thereby enabling to provide at least a refracting element (22) and a reflecting element (14) on either side of the sample (16) and hence to place the source and the sensor on the same side relative to said spot.  
[origin: WO0206779A2] The invention concerns an ellipsometer comprising: a source (2) capable of emitting a broadband ray (4), a polarizer (10) for producing a polarised incident beam (12) adapted to illuminate a sample (16) according to at least a selected angle; an analyzer (24) providing an output beam (28) in response to said reflected beam (20) and at least a reflecting optical element (14) arranged between the source (2) and the sample (16) and/or between the sample (16) and the sensor, and capable of focusing the incident beam (12) and/or the reflected beam (20) according to a selected spot. The ellipsometer further comprises at least a first refracting optical element (22) arranged between the sample (16) and the sensor and/or between the source (2) and the sample (16) to collect and focus said reflected beam and/or said incident beam, thereby enabling to provide at least a refracting element (22) and a reflecting element (14) on either side of the sample (16) and hence to place the source and the sensor on the same side relative to said spot.

IPC 1-7  
**G01J 4/04**

IPC 8 full level  
**G01J 3/447** (2006.01); **G01J 4/04** (2006.01); **G01N 21/21** (2006.01)

CPC (source: EP KR US)  
**G01J 4/04** (2013.01 - EP US); **G01N 21/21** (2013.01 - KR); **G01N 21/21** (2013.01 - EP US)

Citation (search report)  
See references of WO 0206780A1

Citation (examination)  
US 5859424 A 19990112 - NORTON ADAM E [US], et al

Designated contracting state (EPC)  
AT BE CH CY DE DK ES FI FR GB GR IE IT LI LU MC NL PT SE TR

DOCDB simple family (publication)  
**WO 0206779 A2 20020124**; **WO 0206779 A3 20020328**; AU 7070101 A 20020130; AU 7645601 A 20020130; EP 1301763 A2 20030416; EP 1301764 A1 20030416; FR 2811761 A1 20020118; FR 2811761 B1 20021011; JP 2004504590 A 20040212; JP 2004504591 A 20040212; KR 100846474 B1 20080717; KR 20030022292 A 20030315; KR 20030026322 A 20030331; US 2004027571 A1 20040212; US 2004070760 A1 20040415; US 6819423 B2 20041116; US 7230701 B2 20070612; WO 0206780 A1 20020124

DOCDB simple family (application)  
**FR 0102305 W 20010716**; AU 7070101 A 20010628; AU 7645601 A 20010716; EP 01949572 A 20010628; EP 01954108 A 20010716; FR 0009318 A 20000717; FR 0102072 W 20010628; JP 2002512640 A 20010716; JP 2002512641 A 20010628; KR 20037000770 A 20030117; KR 20037000771 A 20030117; US 33341503 A 20030911; US 33341603 A 20030116